

N Channel MOSFET

Lead Free Package and Finish

Applications:

- Adapter & Charger
- AC-DC Switching Power Supply
- LED driving power
- PC Power Supply

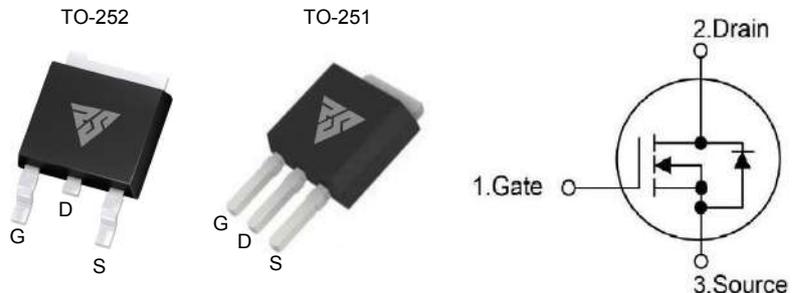
I_D	$R_{DS(ON)}(Typ.)$	V_{DSS}
4A	2.0Ω	650V

Features:

- 100% avalanche tested
- Ultra low gate Charge
- Low Cress
- Fast switching capability
- RoHS Compliant

Ordering Information

Part Number	Package	Marking
RS4N65D	TO-252	RS4N65D
RS4N65MD	TO-251	RS4N65MD



Not to Scale

Absolute Maximum Ratings $T_c=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	RS4N65D	Units
V_{DSS}	Drain-to-Source Voltage (Note*1)	650	V
I_D	Continuous Drain Current	4	A
$I_{D@ 100^\circ\text{C}}$	Continuous Drain Current	2.5	
I_{DM}	Pulsed Drain Current (Note*2)	16	
PD	Power Dissipation	38	W
	Derating Factor above 25°C	0.3	W/°C
VGS	Gate-to-Source Voltage	±30	V
EAS	Single Pulse Avalanche Energy L=29mH IAS=4A VDD=50V RG=25Ω TJ=25°C	290	mJ
TL TPKG	Maximum Temperature for Soldering	300 260	°C
	Leads at 0.063in(1.6mm)from Case for 10 seconds		
	Package Body for 10 seconds		
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

*Drain Current Limited by Maximum Junction Temperature

Caution:Stresses greater than those listed in the“Absolute Maximum Ratings”Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS4N65D	Units	Test Conditions
$R_{\theta JC}$	Junction-to-Case	2.06	°C/W	Drain lead soldered to water cooled heatsink,PD adjusted for a peak junction temperature of +150°C.
$R_{\theta JA}$	Junction-to-Ambient	62.7		1 cubic foot chamber,free air.

OFF Characteristics $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-to-source Breakdown Voltage	650	--	--	V	$V_{GS}=0V, I_D=250\mu A$
I_{DSS}	Drain-to-Source Leakage Current	--	--	1.0	μA	$V_{DS}=650V, V_{GS}=0V$
I_{GSS}	Gate-to-Source Forward Leakage	--	--	100	nA	$V_{GS}=+30V, V_{DS}=0V$
	Gate-to-Source Reverse Leakage	--	--	-100		$V_{GS}=-30V, V_{DS}=0V$

ON Characteristics $T_J=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	--	2.0	2.5	Ω	$V_{GS}=10V, I_D=2A$
$V_{GS(TH)}$	Gate Threshold Voltage	2.0	--	4.0	V	$V_{GS}=V_{DS}, I_D=250\mu A$

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$t_{d(ON)}$	Turn-on Delay Time	--	16.4	--	nS	$V_{DS}=325V$ $I_D=4A$ $R_G=10\Omega$ (Note:3,4)
t_{rise}	Rise Time	--	19.4	--		
$t_{d(OFF)}$	Turn-OFF Delay Time	--	50.3	--		
t_{fall}	Fall Time	--	21.2	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
C_{iss}	Input Capacitance	--	608.8	--	pF	$V_{GS}=0V$
C_{oss}	Output Capacitance	--	53.6	--		$V_{DS}=25V$
C_{rss}	Reverse Transfer Capacitance	--	3.3	--		$f=1.0MHz$
Q_g	Total Gate Charge	--	11.7	--	nC	$V_{DS}=520V$
Q_{gs}	Gate-to-Source Charge	--	2.6	--		$I_D=4A$
Q_{gd}	Gate-to-Drain("Miller") Charge	--	4.4	--		$V_{GS}=10V$ (Note:3,4)

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	4	A	Integral pn-diode in MOSFET
ISM	Maximum Pulsed Current	--	--	16	A	
VSD	Diode Forward Voltage	--	--	1.5	V	IS=4A, VGS=0V
t _{rr}	Reverse Recovery Time	--	209	--	nS	VGS=0V
Q _{rr}	Reverse Recovery Charge	--	1.2	--	μC	IS=4A, di/dt=100A/μs

Notes:

- *1. T_J=±25°C to +150°C.
- *2. Repetitive rating; pulse width limited by maximum junction temperature.
- *3. Pulse width ≤ 300μs; duty cycle ≤ 2%.
- *4. Basically not affected by temperature.

Typical Feature curve

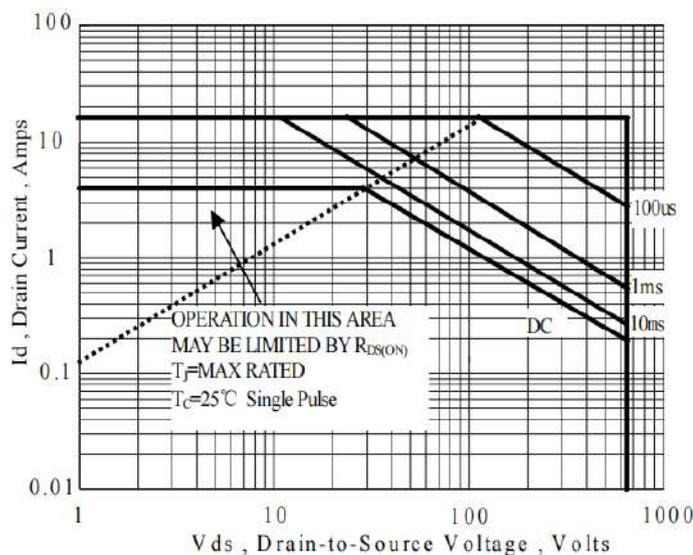


Figure 1 Maximum Forward Bias Safe Operating Area

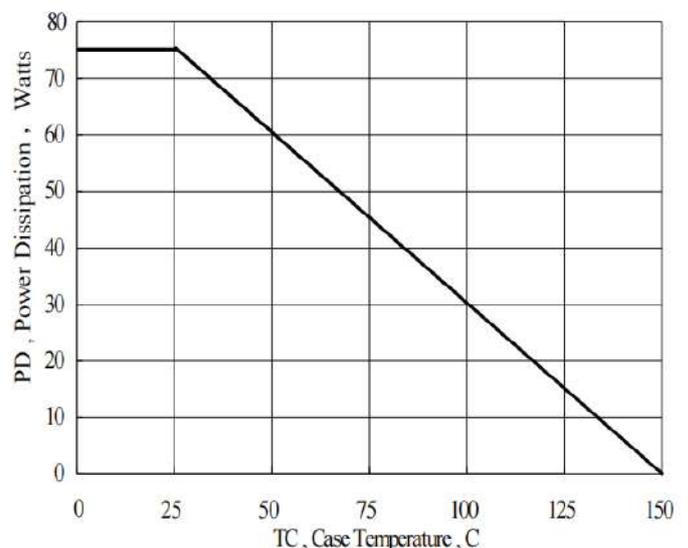


Figure 2 Maximum Power Dissipation vs Case Temperature

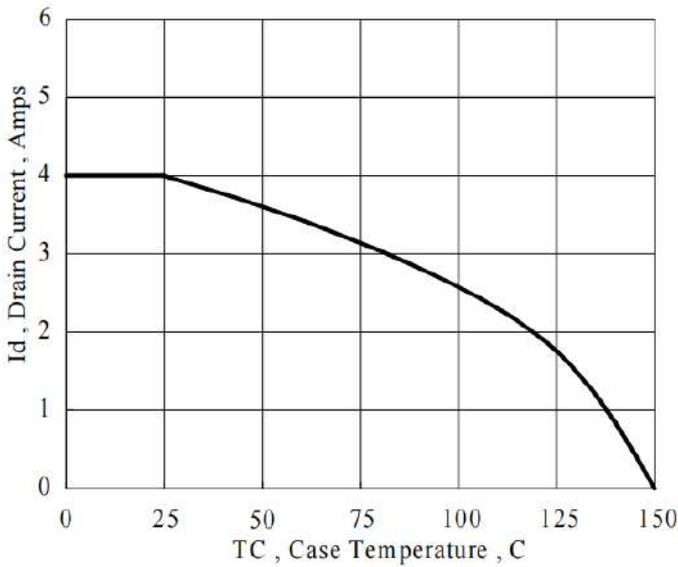


Figure 3 Maximum Continuous Drain Current vs Case Temperature

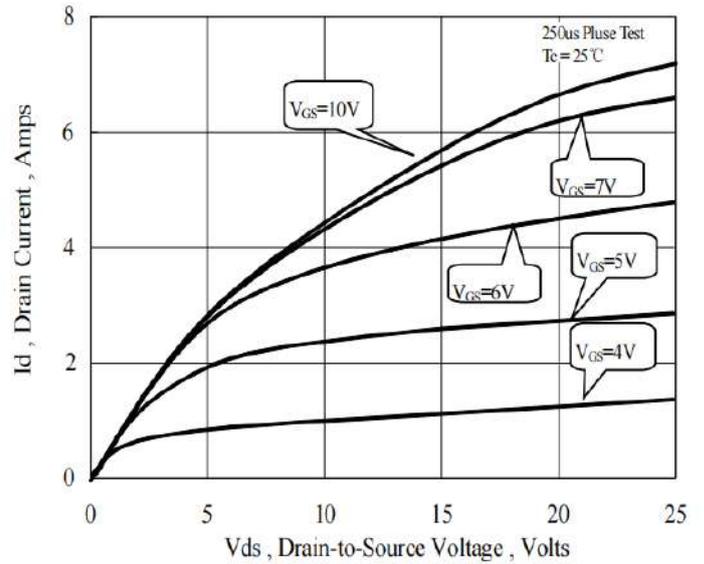


Figure 4 Typical Output Characteristics

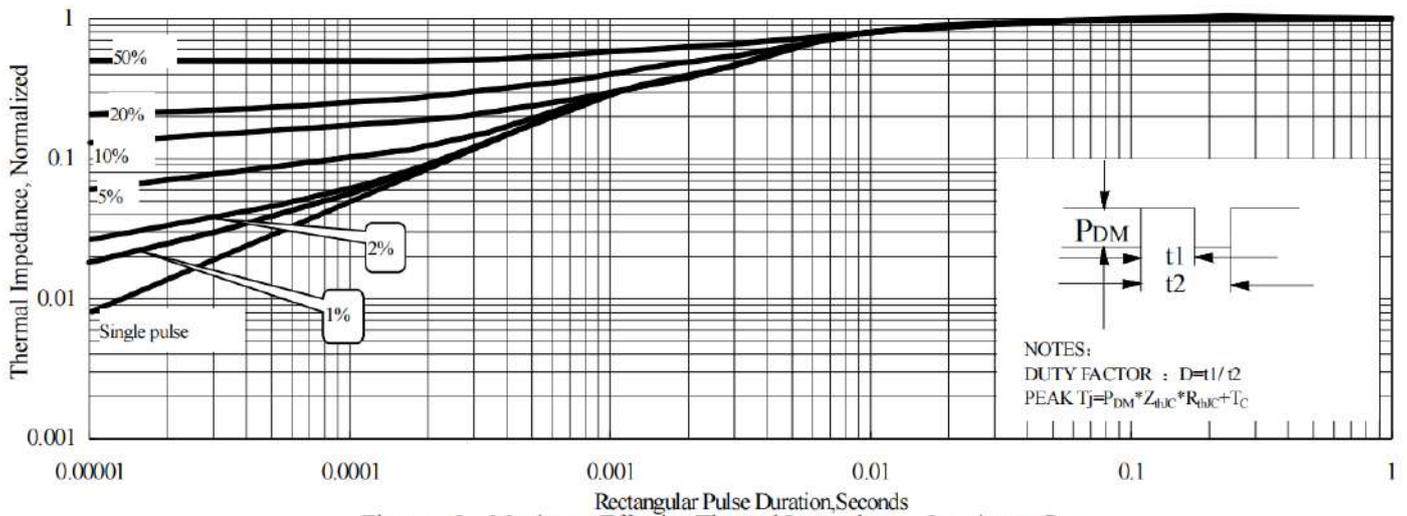


Figure 5 Maximum Effective Thermal Impedance, Junction to Case

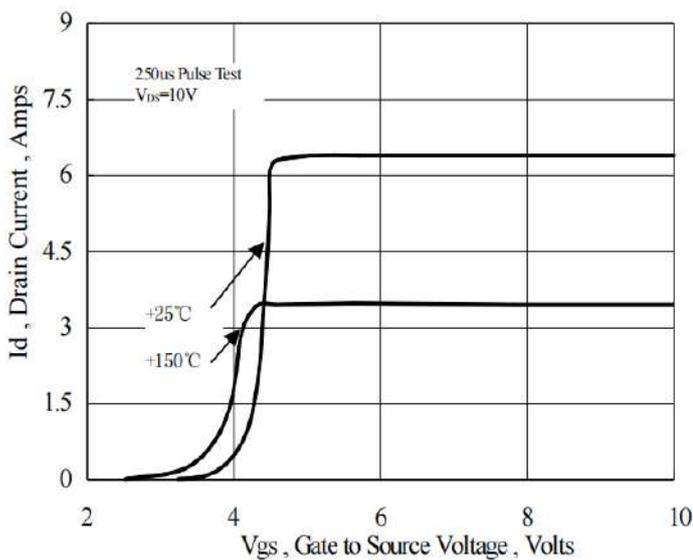


Figure 6 Typical Transfer Characteristics

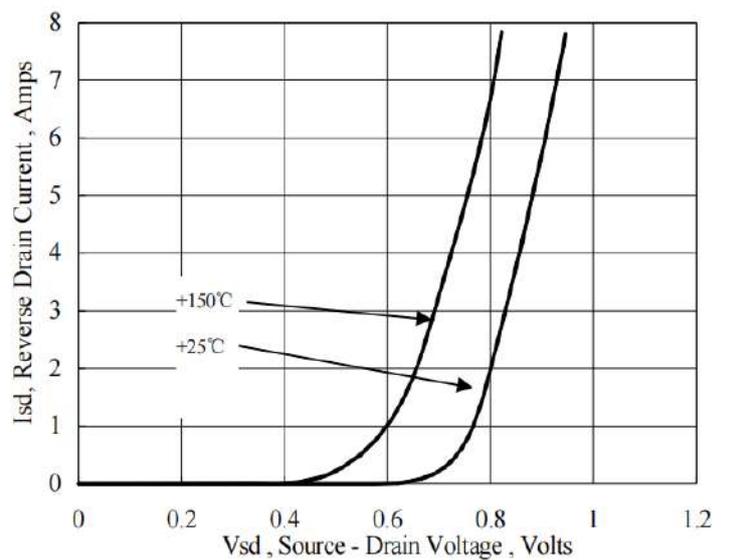


Figure 7 Typical Body Diode Transfer Characteristics

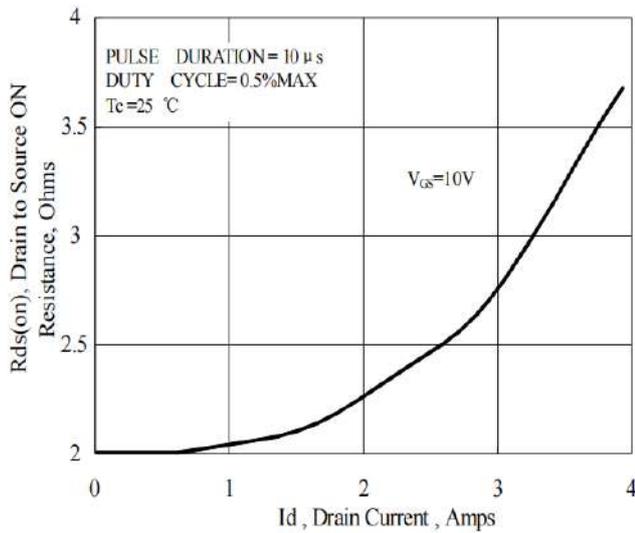


Figure 8 Typical Drain to Source ON Resistance vs Drain Current

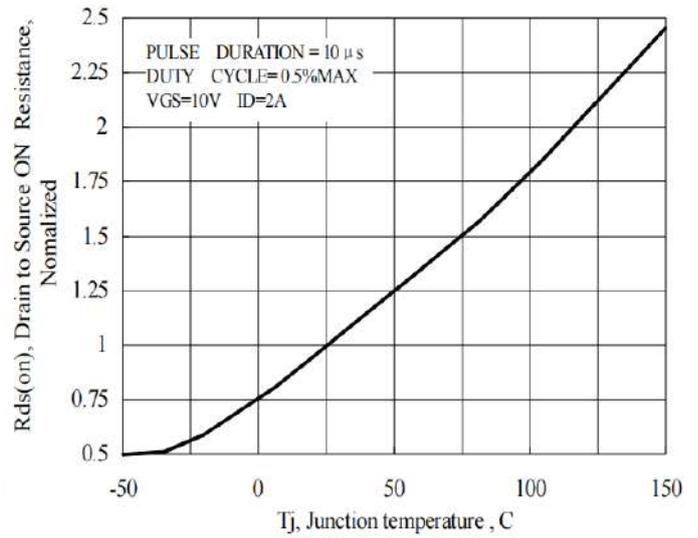


Figure 9 Typical Drain to Source on Resistance vs Junction Temperature

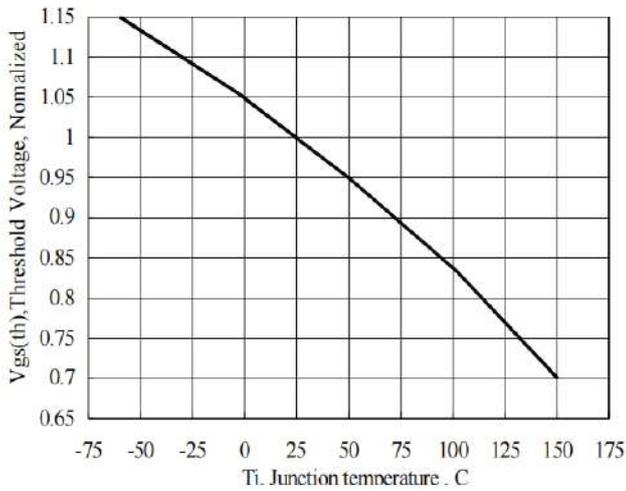


Figure 10 Typical Threshold Voltage vs Junction Temperature

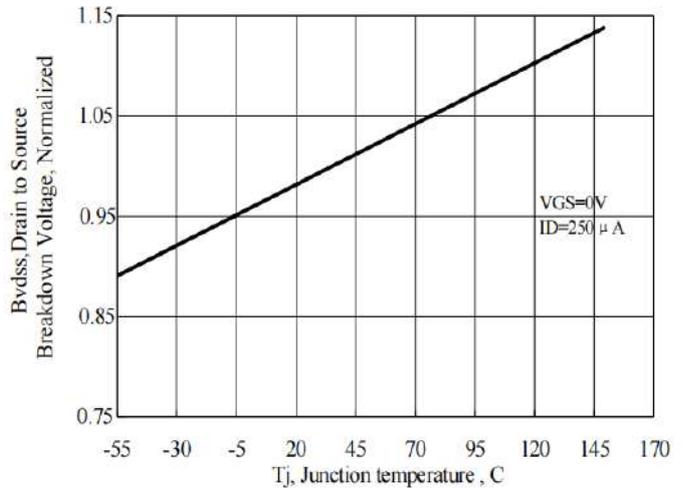


Figure 11 Typical Breakdown Voltage vs Junction Temperature

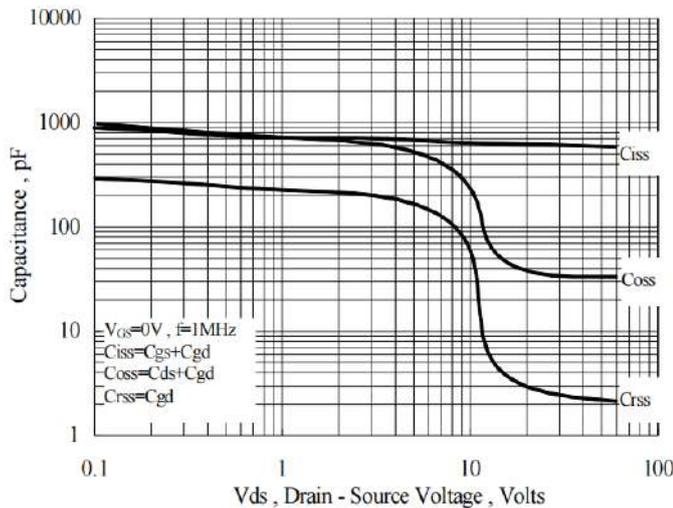


Figure 12 Typical Capacitance vs Drain to Source Voltage

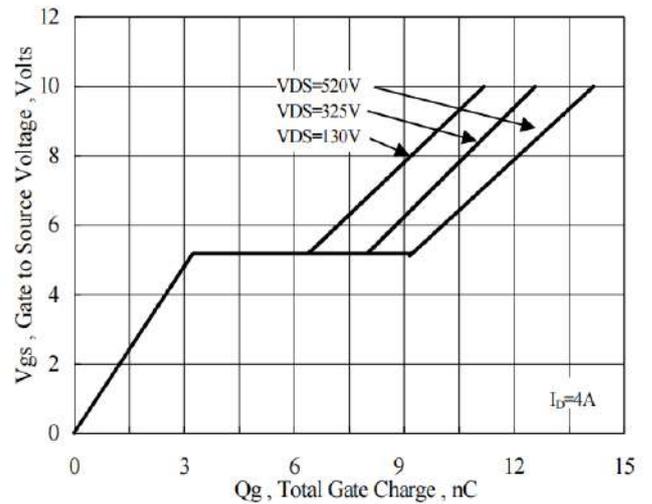


Figure 13 Typical Gate Charge vs Gate to Source Voltage

Test Circuits and Waveforms

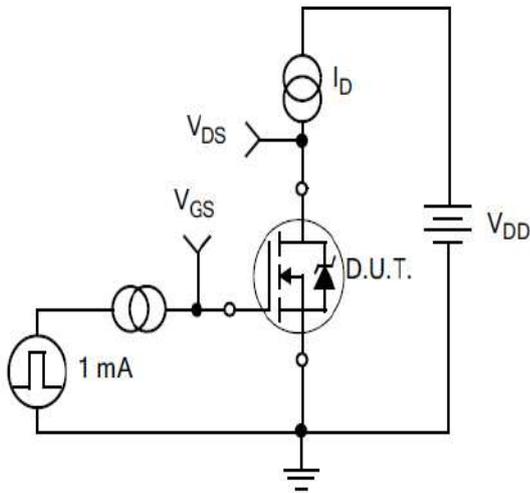


Figure 11.
Gate Charge Test Circuit

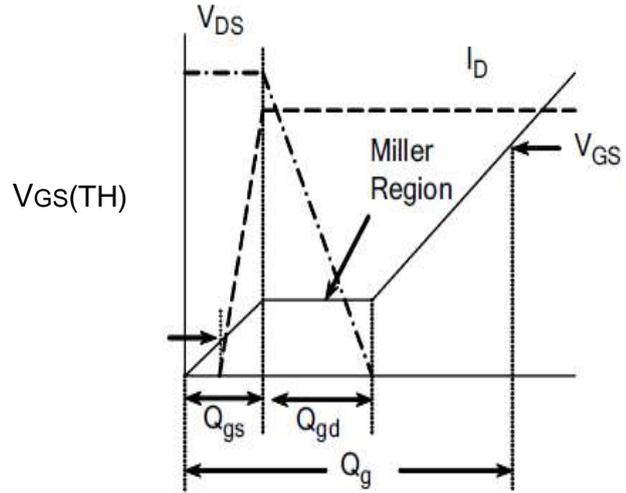


Figure 12.
Gate Charge Waveform

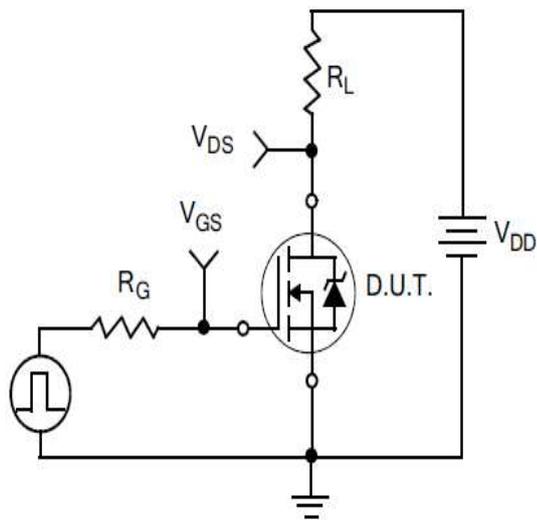


Figure 13.
Resistive Switching Test Circuit

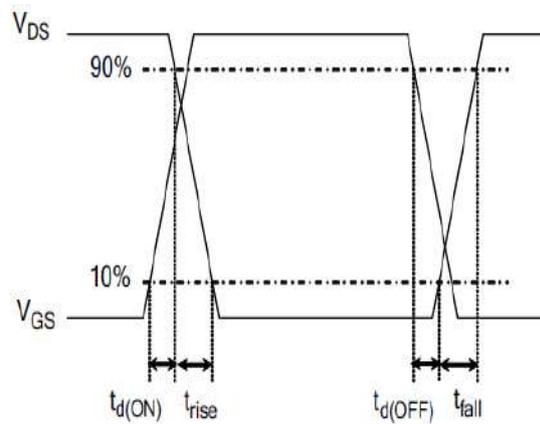


Figure 14.
Resistive Switching Waveforms

Test Circuits and Waveforms

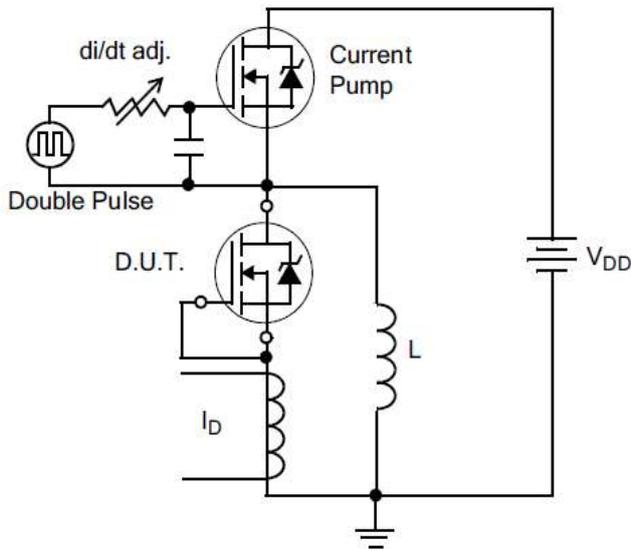


Figure15.Diode Reverse Recovery Test Circuit

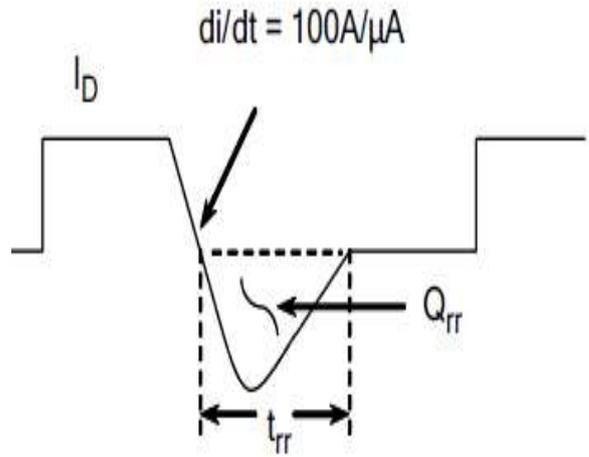


Figure16.Diode Reverse Recovery Waveform

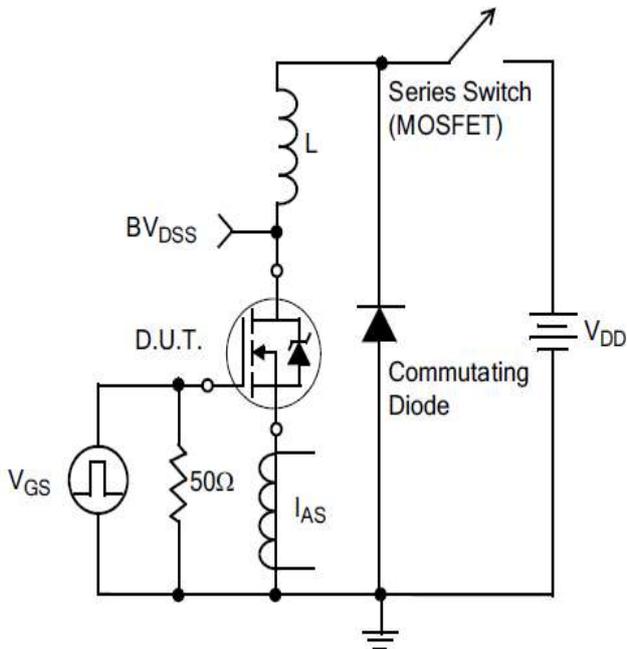
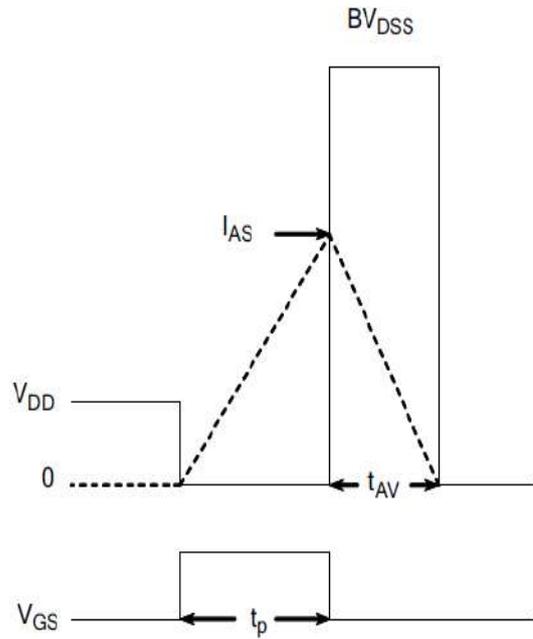


Figure17.Unclamped Inductive Switching Test Circuit



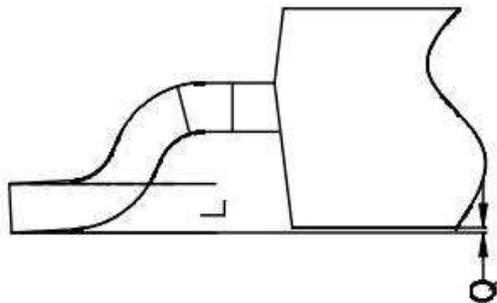
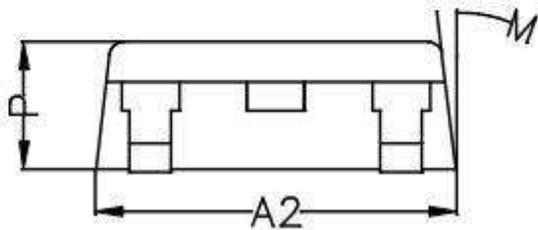
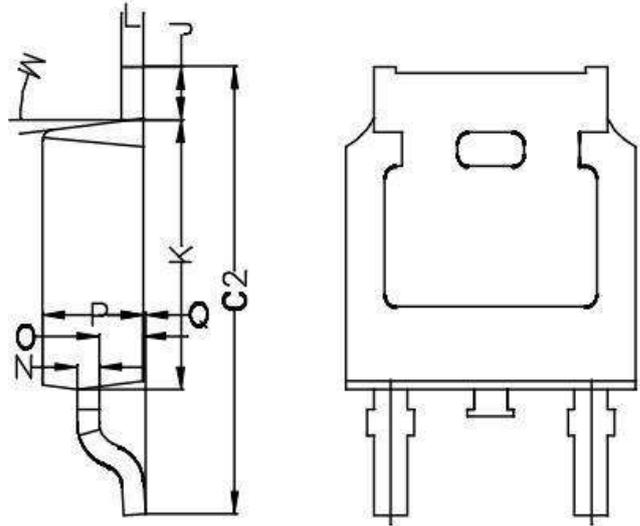
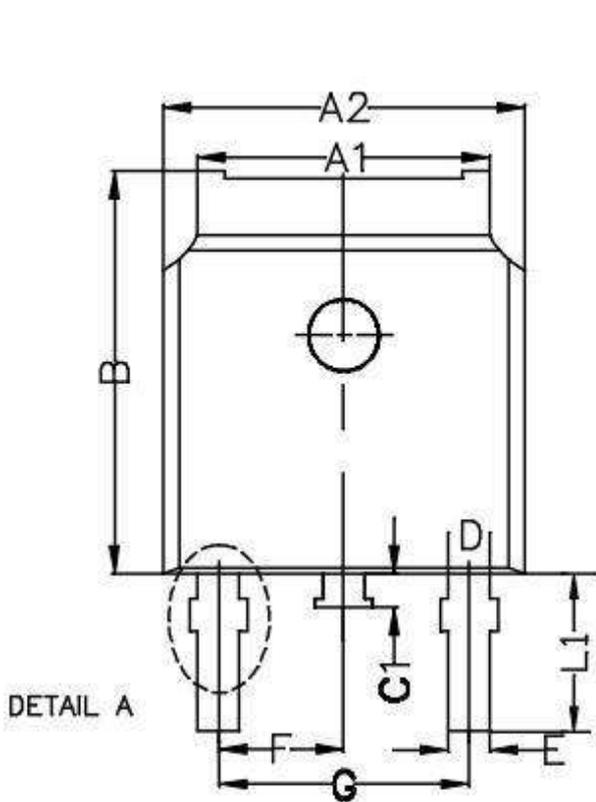
$$EAS = \frac{I_{AS}^2 L}{2}$$

Figure18.Unclamped Inductive Switching Waveforms

Package outline drawing

TO-252

Unit:mm

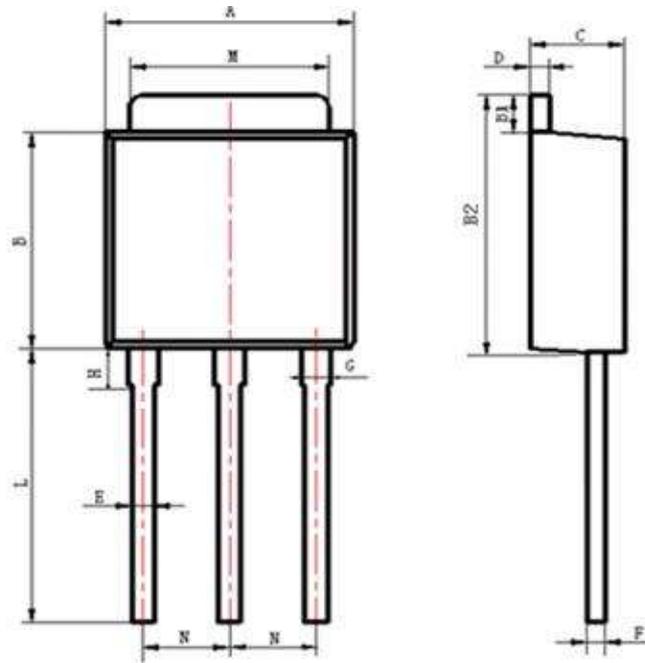


Symbol	Min	Non	Max
A1	5.22	5.32	5.42
A2	6.55	6.60	6.65
B	7.05	7.10	7.15
C1	0.70	0.80	0.90
C2	9.70	9.90	10.10
D	1.00 REF.		
E	0.76 REF.		
F	2.286 REF.		
G	4.572 REF.		
J	0.95	1.00	1.05
K	6.05	6.10	6.15
L	0.508 REF.		
L1	2.65	2.80	2.95
M	7° REF.		
N	0.508 REF.		
O	0.96	1.01	1.06
P	2.25	2.30	2.35
Q	0.00	0.05	0.10

Package outline drawing

TO-251

Unit:mm



Items	Values(mm)	
	MIN	MAX
A	6.30	6.90
B	5.20	6.30
B1	0.70	1.30
B2	6.80	7.40
C	2.10	2.50
D	0.30	0.60
E	0.50	0.86
F	0.30	0.60
G	0.70	1.00
H	1.40	2.40
L*	9.00	9.80
M	5.10	5.50
N	2.09	2.49

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